

## UNISONIC TECHNOLOGIES CO., LTD

UTT200N03 Power MOSFET

# 200A, 30V N-CHANNEL POWER MOSFET

#### ■ DESCRIPTION

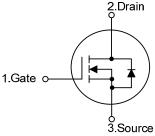
The UTC **UTT200N03** is a N-channel MOSFET using UTC's advanced technology to provide customers with a minimum on-state resistance and superior switching performance.

The UTC **UTT200N03** is generally applied in DC to DC convertor or synchronous rectification

#### ■ FEATURES

- \* Fast Switching
- \* 100% Avalanche Tested
- \* High Power and Current Handling Capability
- \* RoHS Compliant

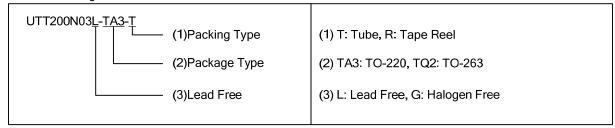
#### ■ SYMBOL



### ■ ORDERING INFORMATION

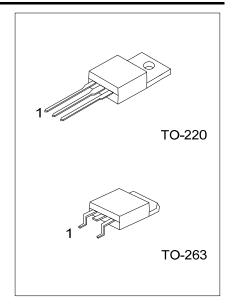
Ordering Number		Doolsons	Pin	Doolsing			
Lead Free	Halogen Free	Package	1	2	3	Packing	
UTT200N03L-TA3-T	UTT200N03G-TA3-T	TO-220	G	D	S	Tube	
UTT200N03L-TQ2-T	UTT200N03G-TQ2-T	TO-263	G	D	S	Tube	
UTT200N03L-TQ2-R	UTT200N03G-TQ2-R	TO-263	G	D	S	Tape Reel	

Note: Pin Assignment: G: Gate D: Drain S: Source



#### ■ MARKING INFORMATION





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#### ■ ABSOLUTE MAXIMUM RATINGS [T<sub>C</sub>=25°C, unless otherwise noted (Note 6)]

PARAMETER		SYMBOL	RATINGS	UNIT	
Drain-Source Voltage		$V_{ extsf{DSS}}$	30	V	
Gate-Source Voltage		$V_{GSS}$	±20	V	
Drain Current	Continuous	I <sub>D</sub>	200	Α	
	Pulsed (Note 1)	I <sub>DM</sub>	800	Α	
Single Pulsed Avalanche Energy (Note 2)		E <sub>AS</sub>	864	mJ	
Power Dissipation	T <sub>C</sub> =25°C	Ъ	178	W	
Power Dissipation	Derate above 25°C	$P_D$	1.43	W/°C	
Junction Temperature		TJ	-55~+150	°C	
Storage Temperature		T <sub>STG</sub>	-55~+150	°C	

Note: Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.

#### ■ THERMAL CHARACTERISTICS

PARAMETER	SYMBOL	RATINGS	UNIT	
Junction to Ambient	$\theta_{JA}$	62.5	°C/W	
Junction to Case	$\theta_{JC}$	0.7	°C/W	

#### ■ ELECTRICAL CHARACTERISTICS (T<sub>C</sub>=25°C, unless otherwise noted)

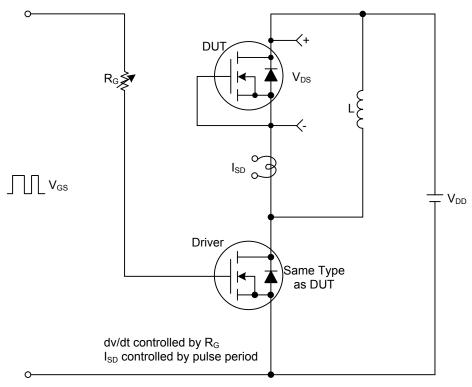
DADAMETED		0)////DOI	TEGT COMPLETIONS	N 41N I	T)/D	14437	LINIT	
PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
OFF CHARACTERISTICS			<del>,</del>					
Drain-Source Breakdown Voltage		$BV_{DSS}$	I <sub>D</sub> =250μA, V <sub>GS</sub> =0V, T <sub>C</sub> =25°C				V	
Drain-Source Leakage Current		I <sub>DSS</sub>	V <sub>DS</sub> =30V, V <sub>GS</sub> =0V			10	μΑ	
Gate- Source Leakage Current	Forward	I <sub>GSS</sub>	V <sub>GS</sub> =+20V, V <sub>DS</sub> =0V			+100	nA	
	Reverse		V <sub>GS</sub> =-20V, V <sub>DS</sub> =0V			-100	nΑ	
ON CHARACTERISTICS								
Gate Threshold Voltage		$V_{GS(TH)}$	$V_{DS}=V_{GS}, I_{D}=250\mu A$ 1.0			3.0	V	
Static Drain-Source On-State Resistance		R <sub>DS(ON)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =80A			2.6	mΩ	
DYNAMIC PARAMETERS					-			
Input Capacitance	nput Capacitance		V <sub>GS</sub> =0V, V <sub>DS</sub> =25V, f=1.0MHz		5490	7300	pF	
Output Capacitance		C <sub>ISS</sub>			1220	1620	pF	
Reverse Transfer Capacitance		$C_{RSS}$			155	233	pF	
SWITCHING PARAMETERS								
Total Gate Charge		$Q_G$			200	350	nC	
Gate to Source Charge		$Q_GS$	V <sub>GS</sub> =10V, V <sub>DS</sub> =25V, I <sub>D</sub> =100A		11		nC	
Gate to Drain Charge		$Q_GD$			40		nC	
Turn-ON Delay Time		$t_{D(ON)}$	V <sub>DD</sub> =30V, I <sub>D</sub> =0.5A, R <sub>GEN</sub> =4.7Ω, V <sub>GS</sub> =10V		70	110	ns	
Rise Time		$t_R$			200	300	ns	
Turn-OFF Delay Time		$t_{D(OFF)}$			1600	2000	ns	
Fall-Time		t <sub>F</sub>			700	1200	ns	
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS								
Maximum Body-Diode Continuous Current		I <sub>S</sub>				200	Α	
Maximum Body-Diode Pulsed Current		I <sub>SM</sub>				800	Α	
Drain-Source Diode Forward Voltage		$V_{SD}$	I <sub>S</sub> =100A, V <sub>GS</sub> =0V			1.3	V	

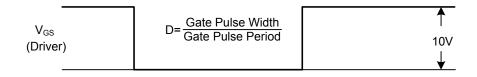
Note: 1. Repetitive Rating: Pulse width limited by maximum junction temperature

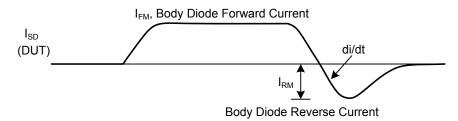
- 2. L = 3mH,  $I_{AS}$  = 24A,  $V_{DD}$  = 30V,  $R_{G}$  = 25 $\Omega$ , Starting  $T_{J}$  = 25 $^{\circ}C$
- 3. Pulse Test: Pulse width ≤ 300µs, Duty cycle ≤ 2%
- 4. Essentially independent of operating temperature

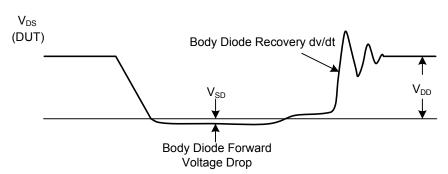
#### ■ TEST CIRCUITS AND WAVEFORMS

#### Peak Diode Recovery dv/dt Test Circuit & Waveforms



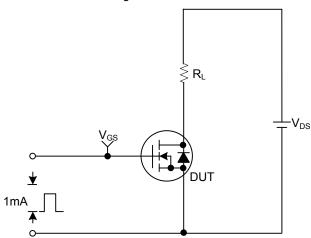




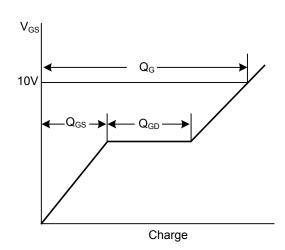


#### ■ TEST CIRCUITS AND WAVEFORMS(Cont.)

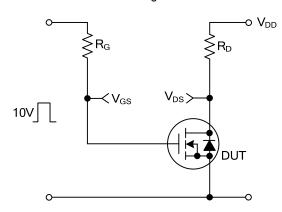
Gate Charge Test Circuit



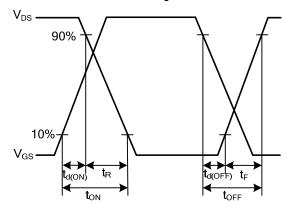
Gate Charge Waveforms



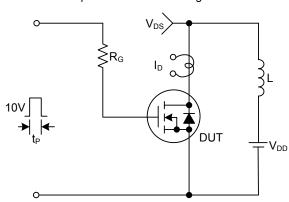
Resistive Switching Test Circuit



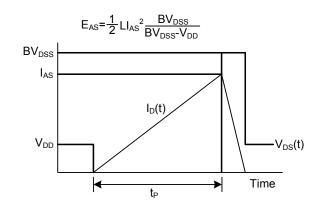
Resistive Switching Waveforms



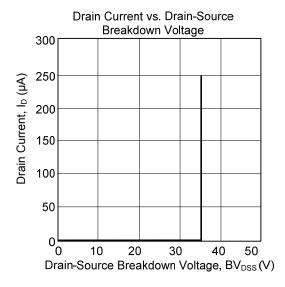
Unclamped Inductive Switching Test Circuit

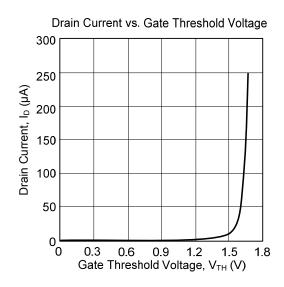


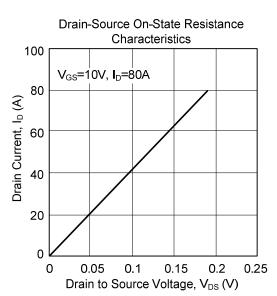
Unclamped Inductive Switching Waveforms

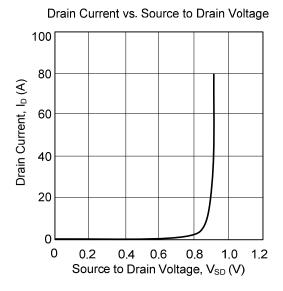


#### ■ TYPICAL CHARACTERISTICS









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